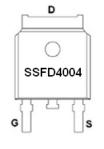
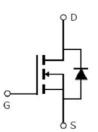


Main Product Characteristics:

V _{DSS}	40V		
R _{DS} (on)	3.2mohm(typ.)		
I _D	145A		







TO-252

Marking and pin
Assignment

Schematic diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



Description:

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V	145①	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	100①	Α
I _{DM}	Pulsed Drain Current ②	580	
P _D @TC = 25°C	Power Dissipation ③	153	W
	Linear Derating Factor	1.02	W/°C
V _{DS}	Drain-Source Voltage	40	V
V _{GS}	V _{GS} Gate-to-Source Voltage		V
E _{AS} Single Pulse Avalanche Energy @ L=0.1mH		281.3	mJ
I _{AS}	Avalanche Current @ L=0.1mH	75	А
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-case ③	_	0.98	°C/W
D	Junction-to-ambient (t $ \leqslant 10 \mathrm{s}$) $ \oplus $	_	62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	40	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
D		_	3.2	4	m0	$V_{GS}=10V, I_{D}=30A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	6.17	_	mΩ	T _J = 125°C
V	Cata threehold voltage	1	_	3	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$V_{GS(th)}$	Gate threshold voltage	_	1.11	_	V	T _J = 125°C
	Drain to Course leekage gurrent	_	_	1		$V_{DS} = 40V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source leakage current	_	_	50	μA	T _J = 125°C
	Cata to Source forward lookage	_	_	100	nA	V _{GS} =20V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100		V _{GS} = -20V
Q_g	Total gate charge	_	52.3	_	nC	I _D = 20A,
Q _{gs}	Gate-to-Source charge	_	20.3	_		V _{DS} =15V,
Q _{gd}	Gate-to-Drain("Miller") charge	_	23.1	_		V _{GS} = 4.5V
t _{d(on)}	Turn-on delay time	_	15.9	_		V _{GS} =10V, V _{DS} =15V,
t _r	Rise time	_	49.0	_		$R_L=0.75\Omega$,
t _{d(off)}	Turn-Off delay time	_	61.6	_	nS	R _{GEN} =3Ω
t _f	Fall time	_	25.6	_		I _D =20A
C _{iss}	Input capacitance	_	6653	_	V _{GS} = 0V	
Coss	Output capacitance	_	632	_	pF	V _{DS} = 15V
C _{rss}	Reverse transfer capacitance	_	603	_		f =1MHz

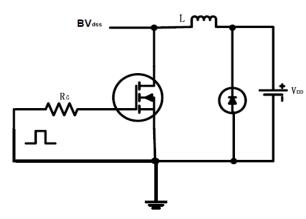
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current		1	145①	А	MOSFET symb
Is	(Body Diode)	_				showing the
1	Pulsed Source Current		_	580	Α	integral reverse
I _{SM}	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.72	1.2	V	I _S =2.1A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	30.8	_	nS	$T_J = 25^{\circ}C$, $I_F = 20A$, $di/dt =$
Q _{rr}	Reverse Recovery Charge	_	31.1	_	nC	100A/µs

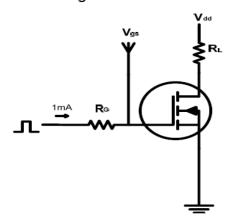


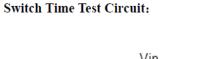
Test circuits and Waveforms

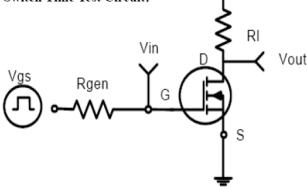
EAS test circuits:



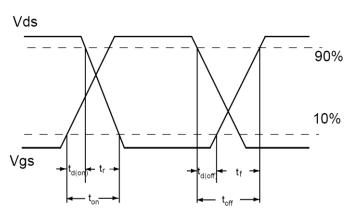
Gate charge test circuit:







Switch Waveforms:



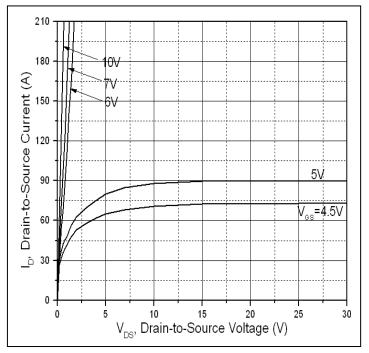
Version: 1.0

Notes:

- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④The value of R_{θJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C.
- ⑤These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =175°C.



Typical electrical and thermal characteristics



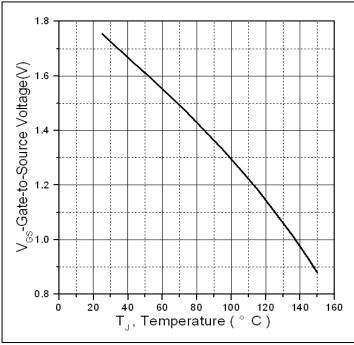


Figure 1: Typical Output Characteristics

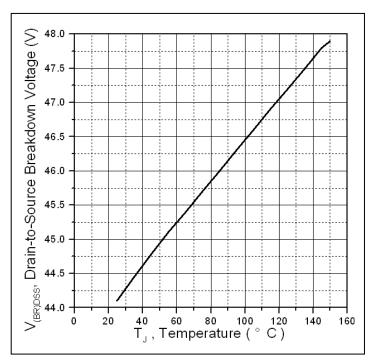


Figure 3. Drain-to-Source Breakdown Voltage vs.
Temperature

Figure 2. Gate to source cut-off voltage

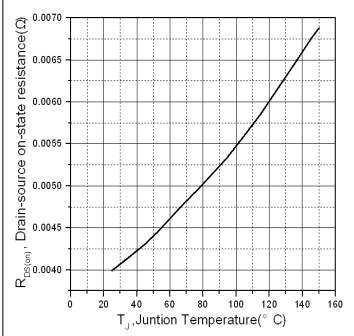
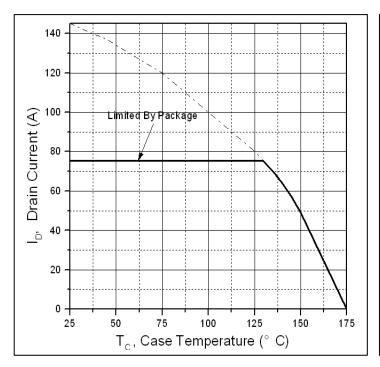


Figure 4: Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics



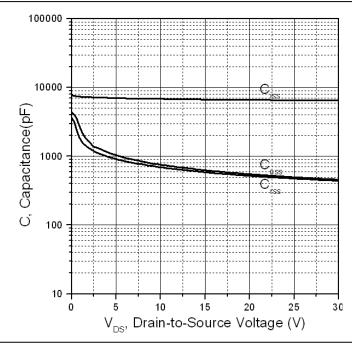


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

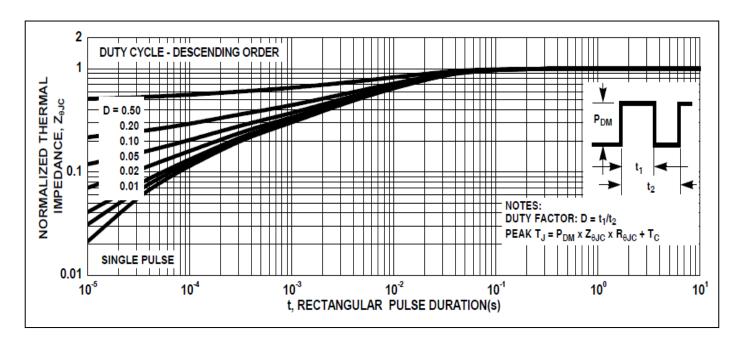
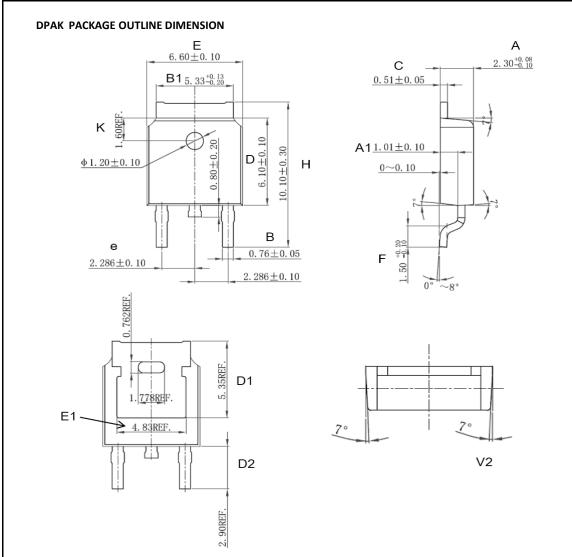


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



Sumbal	Dimension In Millimeters			Dimension In Inches		
Symbol	Min	Nom	Max	Min	Nom	Max
Α	2.200	2.300	2.380	0.087	0.091	0.094
A1	0.910	1.010	1.110	0.036	0.040	0.044
В	0.710	0.760	0.810	0.028	0.030	0.032
B1	5.130	5.330	5.460	0.202	0.210	0.215
С	0.460	0.510	0.560	0.018	0.020	0.022
D	6.000	6.100	6.200	0.236	0.240	0.244
D1		5.350 (REF)		0.211 (REF)		
D2		2.900 (REF)		0.114 (REF)		
Е	6.500	6.600	6.700	0.256	0.260	0.264
E1		4.83 (REF)	4.83 (REF) 0.190 (REF)			
е	2.186	2.286	2.386	0.086	0.090	0.094
Н	9.800	10.100	10.400	0.386	0.398	0.409
F	1.400	1.500	1.700	0.055	0.059	0.067
K		1.600 (REF)		0.063 (REF)		
V2		8 ⁰ (REF)			8 ⁰ (REF)	·



Ordering and Marking Information

Device Marking: SSFD4004

Package (Available)
DPAK (TO-252)
Operating Temperature Range
C: -55 to 175 °C

Devices per Unit

Option1:

Package Type	Units/Tap e	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton	Units/Carton Box
				Box	
TO-252	2500	2	5000	7	35000

Option2:

Package Type	Units/Tap e	Tapes/Inner Box	Units/Inner Box	Inner Boxes/Carton	Units/Carton Box
				Box	
TO-252	2500	1	2500	10	25000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 175℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ or 175℃ @	168 hours	3 lots x 77 devices
Temperature	100% of Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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